



The Testcenter facility 'LoRa<sup>®</sup> Test Lab' within IMST GmbH is recognized by the LoRa<sup>®</sup> Alliance for testing in accordance to the LoRaWAN<sup>®</sup> Specification V1.0.4

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# **Report for Certification by Similarity according to LoRaWAN<sup>®</sup> V1.0.4 (Class A & Temporary Class C)**

for the Device

**“Serie 110 Circum“**

for the Customer

**“HBI Bisscheroux”**

Jens Lerner

Yavuz Turan

10<sup>th</sup> May, 2023

## Administrative Summary

Location: IMST GmbH, Test Centre, Kamp-Lintfort, Germany

Responsible Test Engineer: Yavuz Turan, Jens Lerner

Subject: Test of Conformance to LoRaWAN® Specification V1.0.4

Company and Contact Information:

HBI Bisscheroux

Hofdwarsweg 14

6161DD Geleen

Netherlands

Checked Device: Serie 110 Circum

Hardware version: B

Firmware version: 242-120-121

Type and Version of used Stack: STM32Cube\_FW\_WL

Original End-device identifier: Godwit module

LoRaWAN® Device Class: Class A & Temporary Class C

LoRaWAN® Specification Version: V1.0.4

LoRaWAN® Regional Parameters Version: RP2\_v1.0.3

Certification requirements: LoRa End Device Certification by Similarity V1.1

Frequency band(s): 868 MHz

Type of Certification by Similarity:

Case 1: End-device certification using a certified module

Variant device differences to the referenced certified device:

- Same LoRa transceiver
- Same LoRaWAN protocol SW version
- Same MCU Core
- Same Clock design and implementation

Brief description of the differences between the primary and the variant device

Various housings

Date: 10<sup>th</sup> May, 2023

The Test Report, No. 6230253 has the following conclusion:

**The device fulfils the requirements.**

Responsibility:   
Yavuz Turan  
Test Engineer

Approved:   
Jens Lerner  
Quality Engineer

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